

THE INFLUENCE OF γ -RADIATION ON RELAXING PROPERTIES OF DOPED VANADIUM CRYSTALS TlInS_2

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The influence of γ -radiation on relaxing properties of $\text{TlInS}_2\langle\text{V}\rangle$ compound has been studied. It has been established, that the Fogel-Fulcher temperature T_f shifts to the side of low temperatures in this compound, and Bernce temperature T_d shifts to the side of high temperatures. In the result, the temperature interval of existence of relaxing state becomes wider on $\sim 40\text{K}$.

Our previous investigations [1-5] show, that doping of TlInS_2 crystal by the some impurities leads to the strong relaxation of dielectric receptivity in the region of disproportionated phase. It has been established, the appearance of nano-sized polar domains, leading to the fact, that the state of dipole and ferroelectric glass precedes the ordered phase. The doping atoms, leading to the appearance of the relaxing state, create the capture levels in the forbidden band of semiconductor ferroelectric TlInS_2 . The charge carriers, settling these levels, are spatially limited and in as the result the conductivity in this case is carried out by the tunneling through the potential barriers. This was observed at the investigation of the process of charge transfer in crystals TlInS_2 , doped by atoms Fe, Mn, Cr, B, V, i.e. in these crystals in region of disproportionated phase the non-activated, temperature-independent hopping had been established.

In given paper the results of the investigations of the influence of γ -radiation on relaxing properties of $\text{TlInS}_2\langle\text{V}\rangle$ compound, where V – 0,3 atm.% are presented.

$\text{TlInS}_2\langle\text{V}\rangle$ monocrystals had been grown by the modified method of Bridgmen-Stockberger. The measurements were carried out on the borders, cut perpendicularly to polar axes. The borders had been polishing and covering by the silver paste.

The dielectric constant ϵ was measured with the help of the bridges of alternating current E7-8 (1 kHz) and E7-12 (1 MHz) in the temperature interval 150-250K. The velocity of temperature scanning was 0,1 K/min. The radiation of the samples (Co^{60}) was carried out at the room temperature. The radiation dose was accumulated in the one and the same sample and was 400 Mrad. The measurements $\epsilon(T)$ were carried out after each radiation.

The temperature dependencies of dielectric constant $\epsilon(T)$ of $\text{TlInS}_2\langle\text{V}\rangle$ crystal are given on the fig.1. The investigation of frequency dispersion was carried out on two frequencies of measured field. The shifting of degraded maximum $\epsilon(T)$ in $\text{TlInS}_2\langle\text{V}\rangle$ crystal at the frequency increase was $\sim 3\text{K}$ (fig.1, curves 1-2). As we suppose, the condition of the appearance of relaxing behavior in $\text{TlInS}_2\langle\text{V}\rangle$ crystal is the coincidence of the temperature of phase transition with temperature region of heat filling of local centers. The relaxing properties can be significantly changed by the introduction even the insignificant impurity quantity, influence on charge state of the compound [1,5]. Moreover, the temperature shift of maximum of dielectric constant can achieve the several degrees.

The important peculiarity of ferroelectrics with degraded phase transition is the fact, that the dielectric constant in them higher the T_m temperature changes not on Curie-Weiss law,

but on law $\epsilon^{-1/2} = A + B(T - T_0)$. The dependence $\epsilon^{1/2}(T)$ for the compound $\text{TlInS}_2\langle\text{V}\rangle$ is also given on the fig.1 (curves 3,4). It crosses the temperature axes at $T_f=170\text{K}$ from the side of the high-temperature phase. At this temperature the phase transition from relaxing (nano-domain) state macro-domain (ferroelectric) state is carried out. Also at the temperature $T_d=212\text{K}$ (Berns temperature) the phase transition from paraelectric into relaxing state is carried out.

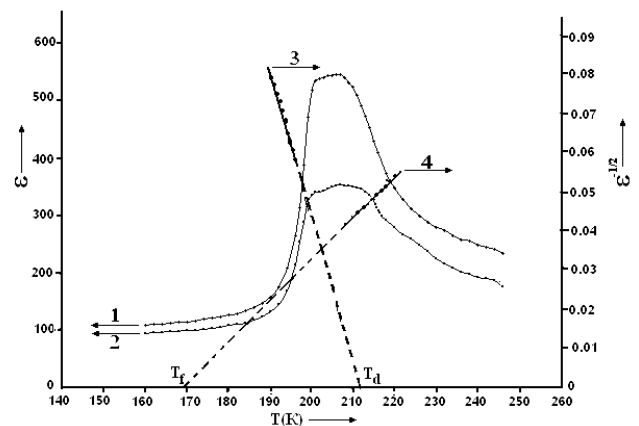


Fig. 1. The temperature dependence of dielectric constant $\epsilon(T)$ of $\text{TlInS}_2\langle\text{V}\rangle$ crystal, measured on the frequencies: 1kHz (curve 1); 1 MHz (curve 2). Curve 3,4 – temperature dependence $\epsilon^{1/2}(T)$ for $\text{TlInS}_2\langle\text{V}\rangle$ (without radiation).

The temperature dependencies of dielectric constant $\epsilon(T)$ at the radiation dose 400 Mrad is given on the fig.2. The radiation doses up to 200Mrad weakly influence on the dependence $\epsilon(T)$, leading only to the decrease of maximum value of investigated dependence. These radiation doses of γ -radiation for these crystals are only slight ionizing radiation and plays the role of activating factor for such processes as the migration of point defects, impurities, domain borders and transitions of metastable states into stable ones. By other words, the radiation-stimulated senescence of the samples, not leading to the temperature changes of phase transitions and energetic spectrum of the crystal [7-8] is observed. At the achievement of the expositional dose in 400 Mrad the radical change of $\epsilon(T)$ dependency is observed. The strong degradation of the $\epsilon(T)$ curve in temperature interval $T_f - T_d$ and its widening in as the high temperature region, so the low one are observed (fig.2).

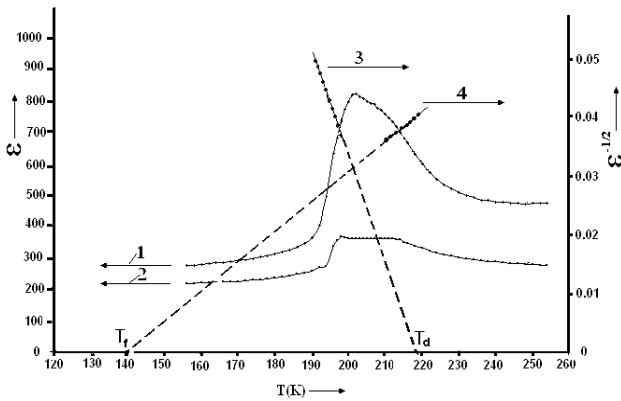


Fig. 2. The temperature dependency of dielectric constant $\epsilon(T)$ of $\text{TIInS}_2\langle V \rangle$ crystal, measured on the frequency 1kHz (curve 1); 1 MHz (curve 2). Curve 3,4 – temperature dependence $\epsilon^{-1/2}(T)$ for $\text{TIInS}_2\langle V \rangle$ (radiation by the dose 400 Mrad).

As it is known [8-9], the degraded character of $\epsilon(T)$ dependency is the necessary condition of the existence of relaxing state. The enough condition is the fact that $\epsilon^{-1/2}(T)$ dependency changes on linear law. This dependence is demonstrated by the fig.2. As it is seen from the figure, $\epsilon^{-1/2}(T)$ dependence crosses the temperature axes at the $T_f=140\text{K}$ (fig.2, curve 3) and at $T_d=220\text{K}$ (fig.2, curve 4) in radiated crystal with high-temperature and low-temperature correspondingly, relatively to the temperature of maximum of $\epsilon(T)$ curve. In relaxing ferroelectrics, this temperature is that one, at which the freezing of polar dipoles takes place and crystal from the state of ferroelectric glass transforms into ordered ferroelectric state. This temperature is also characterized by the fact, that at this the temperature filling of trap centers and localized charged impurities are neutral ones.

As it is known [8], the existence of disordered distribution of the charges in the crystal is the main cause, leading to the degradation of phase transition. The increase of degradation at the radiation by the dose 400 Mrad shows on the fact that the dipole charge centers appear in crystal volume at the radiation. On the given stage of the investigation we can make the supposition about the nature of these dipole centers. These can be the radiation defects, created because of the energy of electron excitations, created

by the radiation. On our opinion, the most probable mechanism of the creation of radiation defects in $\text{TIInS}_2\langle V \rangle$ compound is repeated ionization of boron impurity atom. The created defect increases the energy levels in forbidden crystal band, the heat filling of this level carries out at the more low temperature, in the comparison with non-radiated compound, i.e. the region of the existence of the ferroelectric glass widens.

In the ref [11] the influence of γ -radiation on dielectric constant of Rb_2ZnCl_4 and Pb_2ZnBr_4 crystals in the region of the incommensurate-commensurable phase transition had been investigated. It is shown, that the value of the peak of dielectric constant for both crystals decreases, and their value increases with the increase of the radiation dose. It is established, that the temperature of phase transition for Rb_2ZnCl_4 decreases, and for Pb_2ZnBr_4 it increases and widens with the increase of the radiation dose. The defects of ionizing type (charged defects), which appear in the result of γ -radiation, play in these processes the dominating role. The degradation of the phase transition probably is carried out because of the interaction of polar defects with spontaneous polarization of initial crystal [12]. According to [13], the decrease of the temperature of the phase transition with the increase of radiation dose is caused by the decrease of the concentration of ferroelectric active dipoles in crystal.

The influence of γ -radiation on dielectric and electric properties of TIInS_2 crystals in the region of incommensurable-commensurable phase transition [14] had been studied by us earlier and the possibility of the obtaining of relaxing state in these compounds had been established. It is shown, that the anion atom is charged positively and its normal position in the nod, surrounded by cations, is unstable at two (or more) divisible ionization. In the result of electrostatic interaction with positively charged cations, such positively charged anion is pushed into interstice, where further is neutralized.

Analyzing the literature data and results of own experiments we can say, that γ -radiation strongly influences on relaxing state of $\text{TIInS}_2\langle V \rangle$ compound and widens the temperature interval of its existence. It is also shown, that Fogel-Fulcher T_f temperature shifts to low temperature region and Berns T_d temperature shifts to the high temperature region.

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**VANADIUM ATOMLARI İLƏ AŞQARLANMIŞ $TiInS_2$ KRİSTALLARININ RELAKSOR XASSƏLƏRİNƏ
 γ -ŞUALARIN TƏSİRİ**

γ -şualarının $TiInS_2<V>$ birləşməsinin relaksor xassələrinə təsiri öyrənilmişdir. Müəyyən olunmuşdur ki, Foqel-Fulçer temperaturu T_f temperaturun azalması istiqamətində, Berns temperaturu T_d isə – temperaturun artması istiqamətində sürüşür. Nəticədə relaksor halının mövcud olma temperatur oblasti $\sim 40K$ genişlənir.

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**ВЛИЯНИЕ γ -ОБЛУЧЕНИЯ НА РЕЛАКСОРНЫЕ СВОЙСТВА ЛЕГИРОВАННЫХ ВАНАДИУМ
КРИСТАЛЛОВ $TiInS_2$**

Изучено влияние γ -облучения на релаксорные свойства соединения $TiInS_2<V>$. Установлено, что в этом соединении температура Фогеля-Фулчера T_f смещается в сторону низких температур, а температура Бернса T_d – в сторону высоких температур. В результате температурный интервал существования релаксорного состояния расширяется на $\sim 40K$.

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